

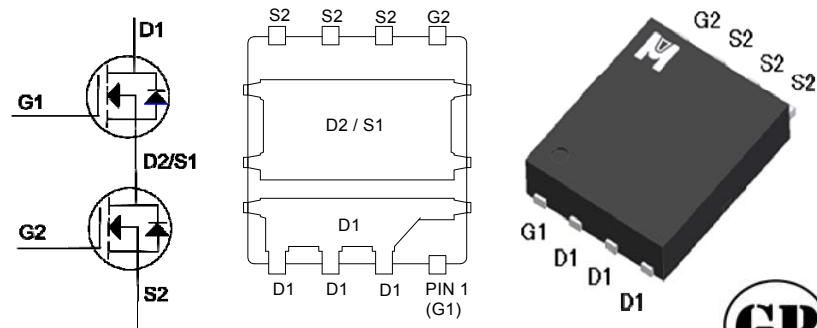
### N-Channel Logic Level Enhancement Mode Field Effect Transistor

#### Product Summary:

	N-CH-Q1	N-CH-Q2
BV <sub>DSS</sub>	40V	40V
R <sub>DSON</sub> (MAX.)	17mΩ	8mΩ
I <sub>D</sub>	41A	57A

UIS, Rg 100% Tested

Pb-Free Lead Plating & Halogen Free



#### ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS		UNIT
		Q1	Q2	
Gate-Source Voltage	V <sub>GS</sub>	±20	±20	V
Continuous Drain Current	T <sub>C</sub> = 25 °C	I <sub>D</sub>	41	57
	T <sub>C</sub> = 100 °C		32	45
Continuous Drain Current	T <sub>A</sub> = 25 °C	I <sub>D</sub>	9	12
	T <sub>A</sub> = 70 °C		7	9.6
Pulsed Drain Current <sup>1</sup>	I <sub>DM</sub>	84	114	
Avalanche Current	I <sub>AS</sub>	30	40	
Avalanche Energy	E <sub>AS</sub>	45	80	mJ
Repetitive Avalanche Energy <sup>2</sup>	E <sub>AR</sub>	22.5	40	
Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	48	69
	T <sub>C</sub> = 100 °C		19	27
Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.01	2.08
	T <sub>A</sub> = 70 °C		1.2	1.3
Operating Junction & Storage Temperature Range	T <sub>j</sub> , T <sub>stg</sub>	-55 to 150		°C

#### THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R <sub>θJC</sub>	Steady State	2.6	1.8
Junction-to-Ambient <sup>3</sup>	R <sub>θJA</sub>	Steady State		
	R <sub>θJA</sub>	t ≤ 10 s		

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

<sup>3</sup>R<sub>θJA</sub> when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.

**ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	Q1	40		V
			Q2	40		
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	Q1	1	1.7	3
			Q2	1	1.7	3
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	Q1			±100
			Q2			±100
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 32V, V <sub>GS</sub> = 0V	Q1			1
			Q2			1
		V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125 °C	Q1			25
			Q2			25
On-State Drain Current <sup>1</sup>	I <sub>D(ON)</sub>	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V	Q1	41		A
			Q2	57		
Drain-Source On-State Resistance <sup>1</sup>	R <sub>D(S)ON</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 6A	Q1		14	17
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 12A	Q2		6.2	8
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 4A	Q1		22	32
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 10A	Q2		7.8	12
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 6A	Q1		15	S
		V <sub>DS</sub> = 5V, I <sub>D</sub> = 12A	Q2		18	
<b>DYNAMIC</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 20V, f = 1MHz	Q1		707	pF
			Q2		1962	
Output Capacitance	C <sub>oss</sub>		Q1		98	
			Q2		245	
Reverse Transfer Capacitance	C <sub>rss</sub>		Q1		81	
			Q2		225	
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> = 15mV, V <sub>DS</sub> = 0V, f = 1MHz	Q1		1.5	Ω
			Q2		1.4	
Total Gate Charge <sup>1,2</sup>	Q <sub>g</sub> (V <sub>GS</sub> =10V)	Q1	Q1		18	

	$Q_g(V_{GS}=4.5V)$	$V_{DD} = 20V, V_{GS} = 10V,$ $I_D = 6A$ $Q2$ $V_{DD} = 20V, V_{GS} = 10V,$ $I_D = 12A$	Q2		47		nS	
			Q1		10			
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$		Q2		24			
			Q1		2.4			
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$		Q2		6.8			
			Q1		6.0			
Turn-On Delay Time <sup>1,2</sup>	$t_{d(on)}$		Q2		16			
			Q1		6			
Rise Time <sup>1,2</sup>	$t_r$		Q2		10			
			Q1		10			
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(off)}$		Q2		18			
			Q1		18			
Fall Time <sup>1,2</sup>	$t_f$		Q2		20			
			Q1		12			
			Q2		15			

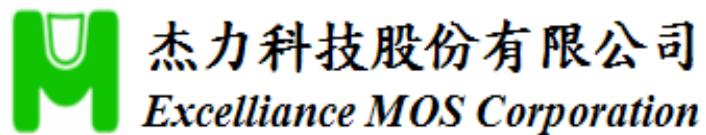
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_c = 25^\circ C$ )

Continuous Current	$I_S$	$I_F = 6A, V_{GS} = 0V$ $I_F = 12A, V_{GS} = 0V$	Q1			41	A
			Q2			57	
Pulsed Current <sup>3</sup>	$I_{SM}$	$I_F = 6A, V_{GS} = 0V$ $I_F = 12A, V_{GS} = 0V$	Q1			84	V
			Q2			114	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 6A, V_{GS} = 0V$ $I_F = 12A, V_{GS} = 0V$	Q1			1.3	nS
			Q2			1.3	
Reverse Recovery Time	$t_{rr}$	$I_F = 6A, dI_F/dt = 100A/\mu S$ $I_F = 12A, dI_F/dt = 100A/\mu S$	Q1		18		nC
			Q2		22		
Reverse Recovery Charge	$Q_{rr}$	$I_F = 6A, dI_F/dt = 100A/\mu S$ $I_F = 12A, dI_F/dt = 100A/\mu S$	Q1		5		nC
			Q2		6		

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

<sup>3</sup>Pulse width limited by maximum junction temperature.



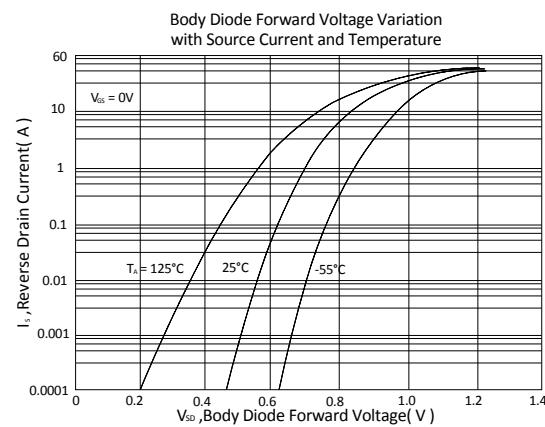
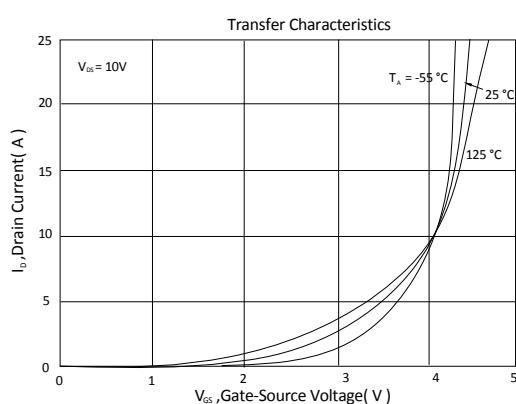
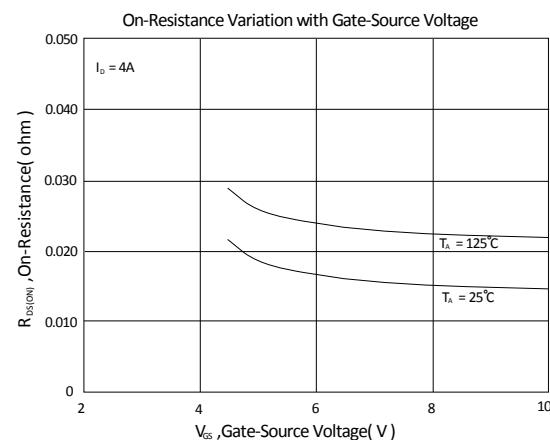
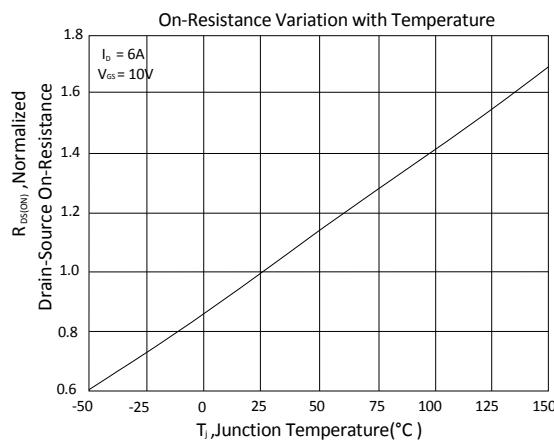
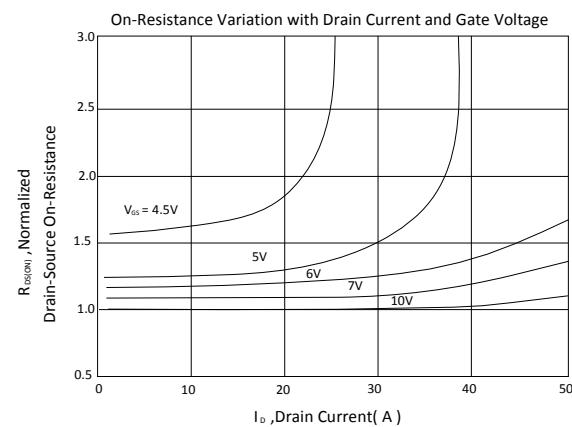
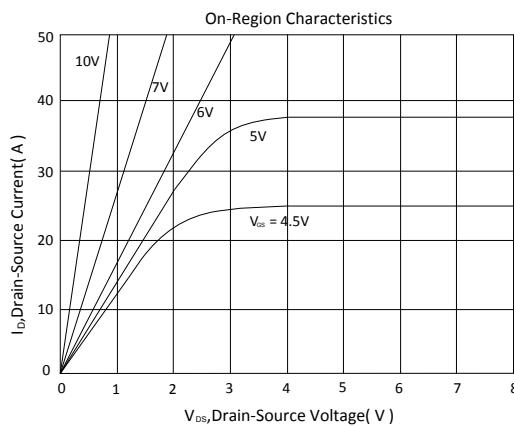
EMB08K04HP

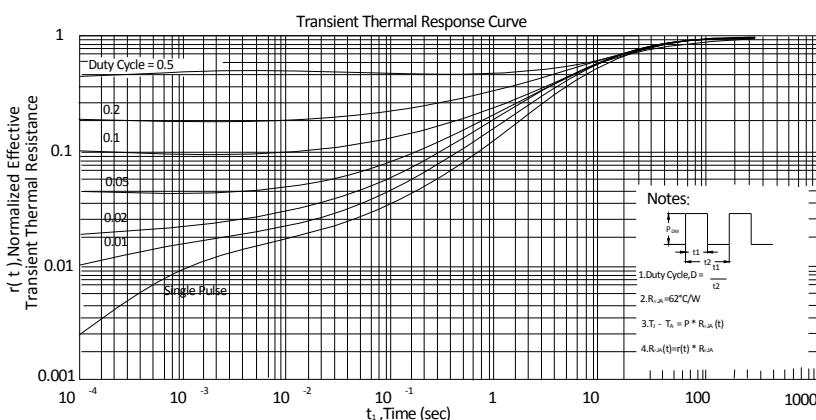
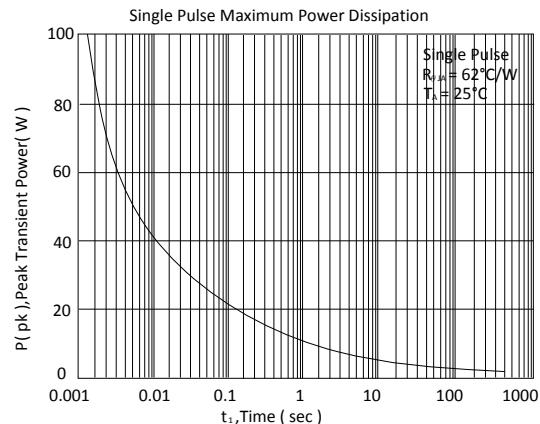
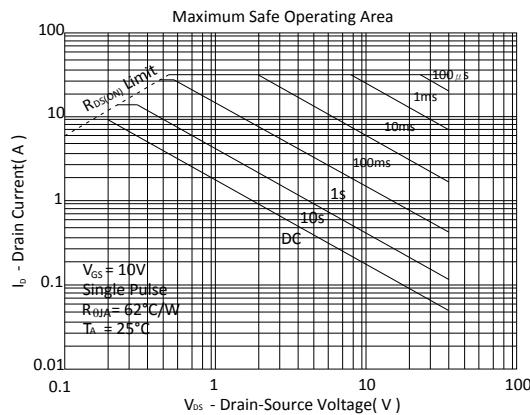
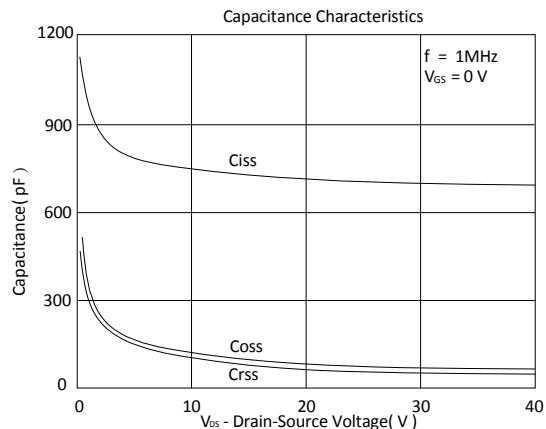
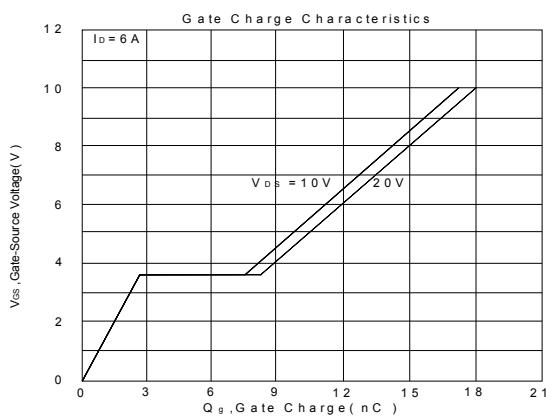
Ordering & Marking Information:

Device Name: EMB08K04HP for Asymmetric Dual EDFN 5 x 6

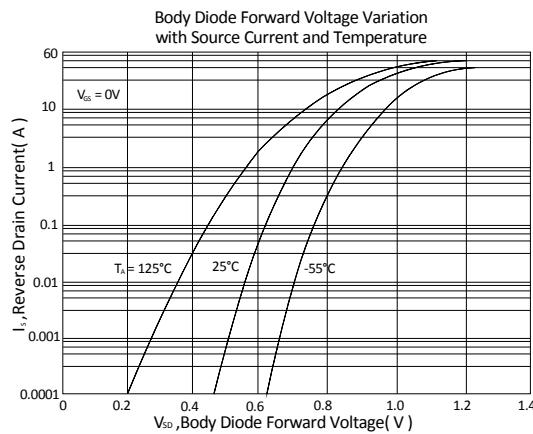
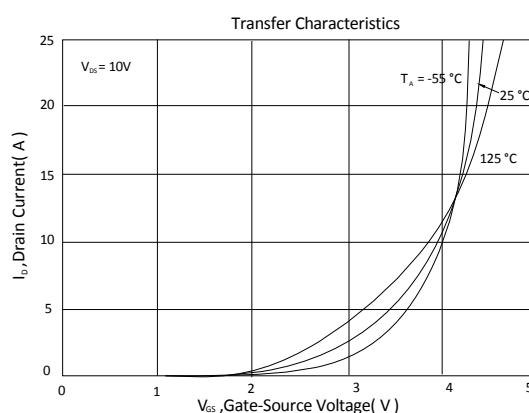
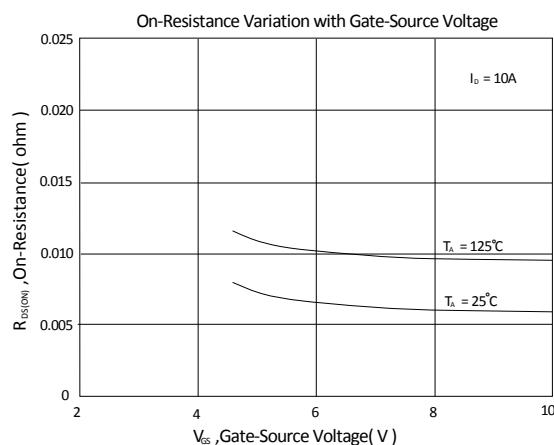
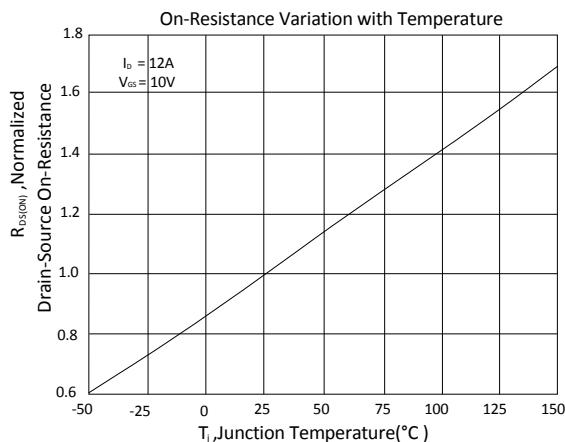
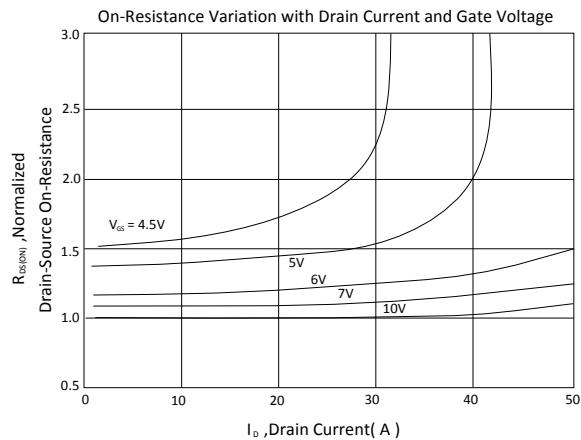
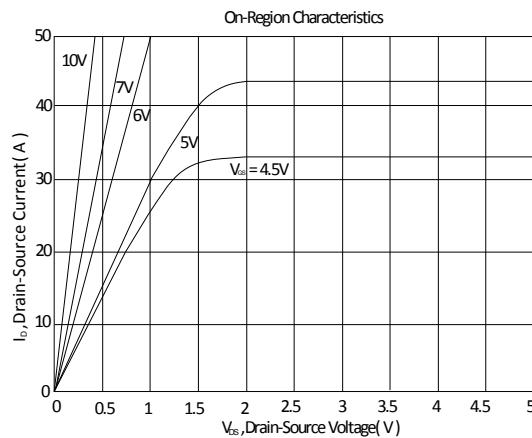


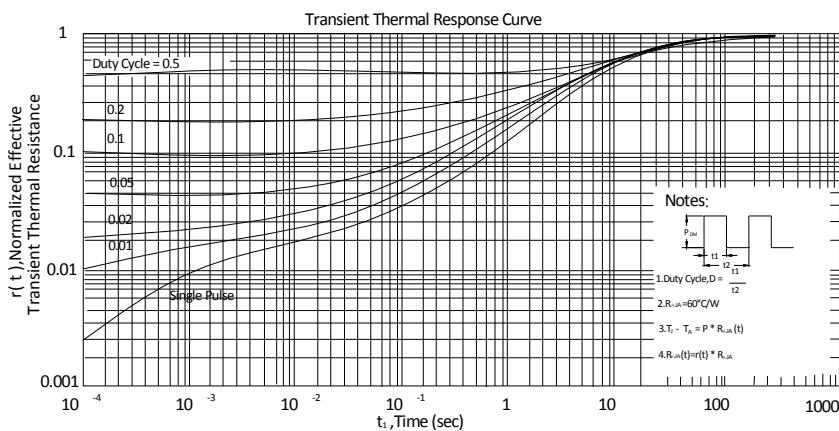
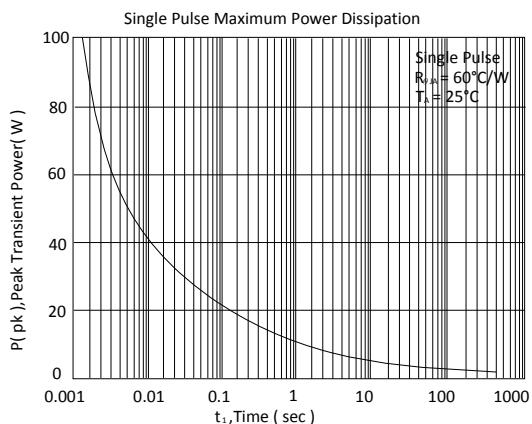
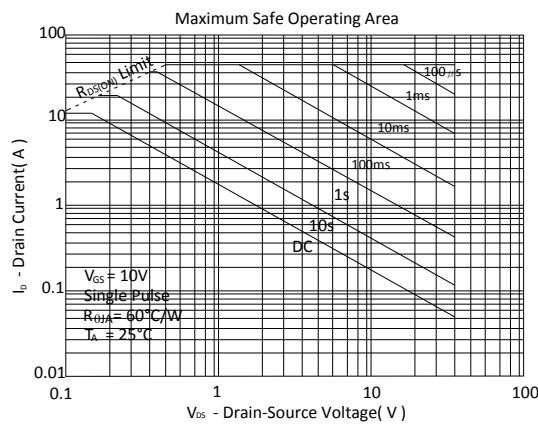
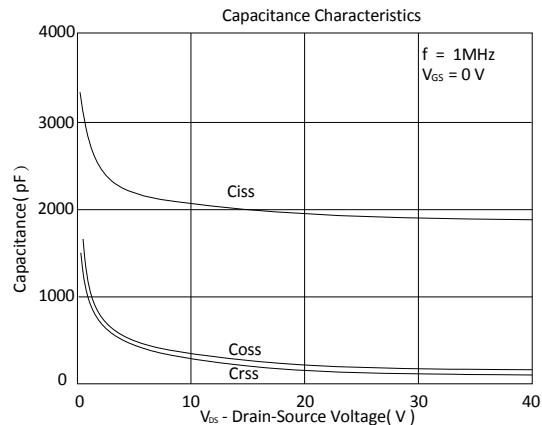
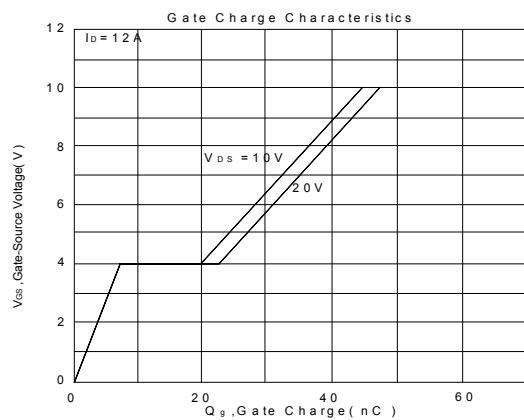
Q1 TYPICAL CHARACTERISTICS



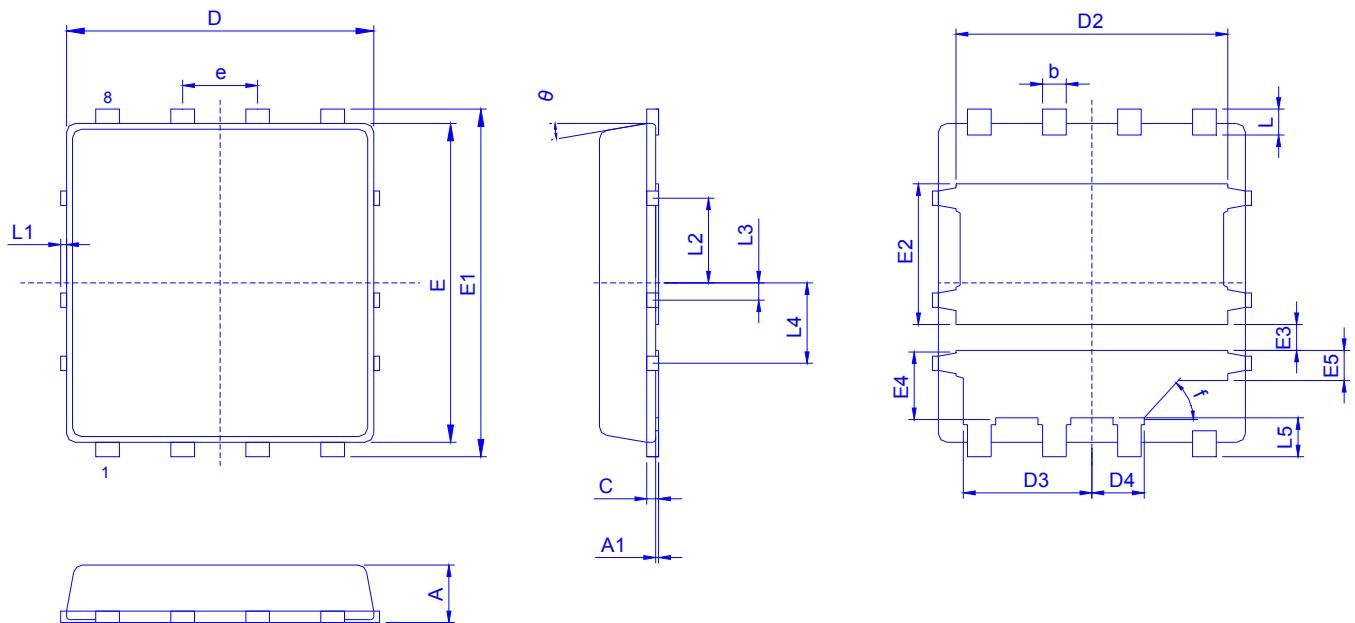


**Q2 TYPICAL CHARACTERISTICS**





Outline Drawing



Dimension in mm

Dimension	A	A1	b	c	D	D2	D3	D4	E	E1	E2	E3	E4	E5
Min.	0.85	0.00	0.35	0.15		4.5	2.125	0.835			2.4	0.40	1.125	0.475
Typ.	0.90		0.40	0.20	5.2	4.6	2.175	0.885	5.55	6.05	2.45	0.45	1.175	0.525
Max.	1.00	0.05	0.45	0.25		4.7	2.225	0.935			2.5	0.50	1.225	0.575

Dimension	e	L	L1	L2	L3	L4	L5	F	θ
Min.		0.35	0	1.375	0.2	1.3	0.575		0°
Typ.	1.27	0.45		1.475	0.3	1.4	0.675	45°	
Max.		0.55	0.1	1.575	0.4	1.5	0.775		10°

Recommended minimum pads

